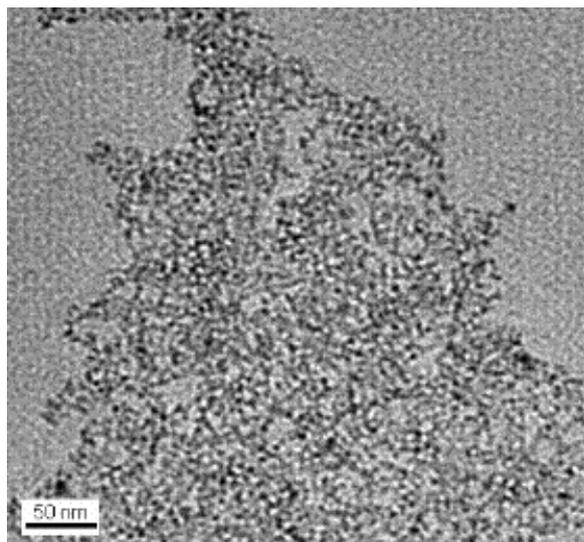
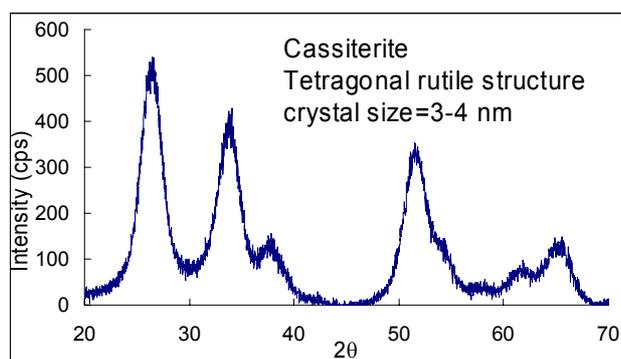


Electronic Supplementary Information

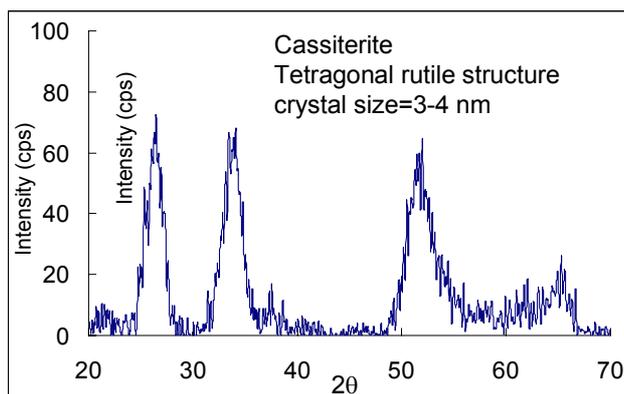


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Fig. S1 TEM image of SnO<sub>2</sub> NPs (aggregated during TEM sample preparation). Scale bar: 50 nm



SnO<sub>2</sub> NPs



SnO<sub>2</sub> NACs

Fig. S2 XRD patterns of SnO<sub>2</sub> NPs and resultant SnO<sub>2</sub> microcapsules. Suspensions were dried prior to XRD measurement. Data were obtained with a powder diffractometer (Rigaku D/Max-2100PC) using unfiltered Cu-K $\alpha$  radiation ( $\lambda = 1.5406 \text{ \AA}$ ) at 40 kV and 40 mA.